Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/621,583	FUJII, KOHEI	
Examiner	Art Unit	
Tu X. Nguyen	2684	

SEARCHED				
Class	Subclass	Date	Examiner	
455	11.1	2/17/2006	TN	
	556			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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(INCLUDING SEA	H NOTES ARCH STRATEG	Y)
	DATE	EXMR
Search East	2/17/2006	TN